

<b>Notice of References Cited</b>	Application/Control No. 10/750,042	Applicant(s)/Patent Under Reexamination YUEH ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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**FOREIGN PATENT DOCUMENTS**

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	N	JP 11143067 A	05-1999	Japan	Hattori	G03F 07/023
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**NON-PATENT DOCUMENTS**

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